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Correction: Structural, electrical, and optical properties of NiO films for surface-enhanced Raman spectroscopy applications

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rsc.li/rsc-advancesCorrection for 'Structural, electrical, and optical properties of NiO films for surface-enhanced Raman spectroscopy applications' by Long Nguyen Hoang *et al.*, *RSC Adv.*, 2025, 15, 17365–17376, <https://doi.org/10.1039/D5RA02866C>.

The authors regret that the affiliations were incorrectly shown in the original manuscript. The corrected list of affiliations is as shown herein.

The Royal Society of Chemistry apologises for these errors and any consequent inconvenience to authors and readers.

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